Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/828,671	OKAYASU, TOSHIYUKI	HIYUKI	
Examiner	Art Unit		
Hai L. Nguyen	2816		

	SEAR	CHED	
Class	Subclass	Date	Examiner
327 {	149,161, 151-156, 162, 261,265	3/26/2005	HLN
	270,273		
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INT	INTERFERENCE SEARCHED				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Shepardize Search	3/28/2005	HLN	